Power MOSFET

30 V, 10.2 A, N-Channel, SO-8

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- Disk Drives
- DC-DC Converters
- Printers

MAXIMUM RATINGS (T₁ = 25°C unless otherwise stated)

Paran	Symbol	Value	Unit		
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain		T _A = 25°C	I _D	8.0	Α
Current R _{θJA} (Note 1)		T _A = 70°C	1	6.4	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	1.49	W
Continuous Drain		T _A = 25°C	Ι _D	6.0	Α
Current R _{θJA} (Note 2)	Steady	T _A = 70°C		4.8	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.82	W
Continuous Drain		T _C = 25°C	I _D	10.2	Α
Current $R_{\theta JC}$, $t \le 10 s$ (Note 1)		T _C = 70°C		8.2	
Power Dissipation $R_{\theta JC}$, $t \le 10 \text{ s(Note 1)}$		T _C = 25°C	P _D	2.4	W
Pulsed Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \mu s$			I _{DM}	56	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to 150	°C
Source Current (Body Diode)			Is	2.4	Α
Single Pulse Drain–to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $V_{DD} = 30$ V, $V_{GS} = 10$ V, $I_L = 7.0$ A _{pk} , $L = 1.0$ mH, $R_G = 25$ Ω)			E _{AS}	24.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	84	°C/W
Junction-to-Ambient – $t \le 10 \text{ s (Note 1)}$	$R_{\theta JA}$	52	
Junction-to-Foot (Drain)	$R_{\theta JF}$	22.5	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	153	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surfacemounted on FR4 board using 1 sq-in pad, 2 oz Cu.
- 2. Surfacemounted on FR4 board using the minimum recommended pad size.

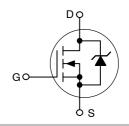


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	13.5 mΩ @ 10 V	10.2 A
	16.5 mΩ @ 4.5 V	10.2 A

N-Channel



1 SO-8 CASE 751 STYLE 12

MARKING DIAGRAM/ PIN ASSIGNMENT

Source Barbara Barbara

4872N = Device Code A = Assembly Location Y = Year

WW = Work Week
■ Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4872NR2G	SO-8 (Pb-Free)	2500/Tape & Reel

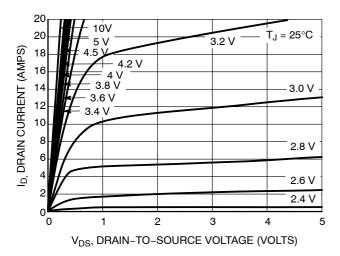
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				13		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	., .,,,	T _J = 25°C			1.0	μΑ
		V _{GS} = 0 V, V _{DS} = 24 V	T _J = 100°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, $I_D = 2$	250 μΑ	1.45		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	10.2 A		9.4	13.5	mΩ
		V _{GS} = 4.5 V, I _D =	9.3 A		13.5	16.5	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	10.2 A		21		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE			=	-	
Input Capacitance	C _{iss}				1136	1700	pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz,	V _{DS} = 15 V		240	370	
Reverse Transfer Capacitance	C _{rss}		ļ		130	200	1
Total Gate Charge	Q _{G(TOT)}				10	15	nC
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_D = 10.2 \text{ A}$			1.3		
Gate-to-Source Charge	Q_{GS}				3.4	5.0	
Gate-to-Drain Charge	Q_{GD}				3.8	5.5	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 10.2 A			20	30	nC
SWITCHING CHARACTERISTICS (No	ote 4)						
Turn-On Delay Time	t _{d(on)}				10	15	ns
Rise Time	t _r	V _{GS} = 10 V, V _{DS} =	= 15 V,		22	35	
Turn-Off Delay Time	t _{d(off)}	I _D = 10.2 A, R _G =	6.0 Ω		23	35	
Fall Time	t _f				5.7	9.0	
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V_{SD}	V 0V 1 0 4 A	T _J = 25°C		0.76	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 2.4 \text{ A}$	T _J = 125°C		0.6		
Reverse Recovery Time	t _{RR}				17.5	27	ns
Charge Time	t _a	V_{GS} = 0 V, d_{IS}/d_{t} = 100 A/ μ s, I_{S} = 10.2 A			8.5	13	
Discharge Time	t _b				9.0	14	
Reverse Recovery Charge	Q _{RR}				6.5	10	nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	- T _A = 25°C			0.66		nH
Drain Inductance	L _D				0.20		nΗ
Gate Inductance	L _G				1.5		nH
	~		1				

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

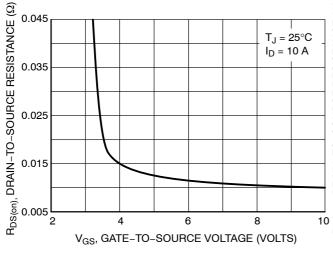
TYPICAL PERFORMANCE CURVES



| V_{DS} ≥ 10 V | V_D

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



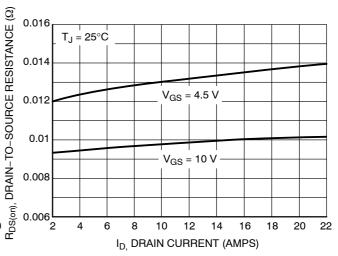
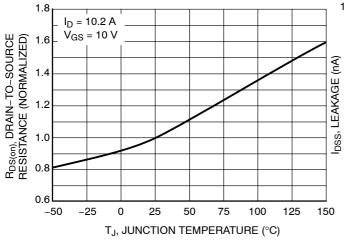


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



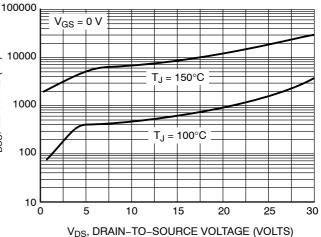


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

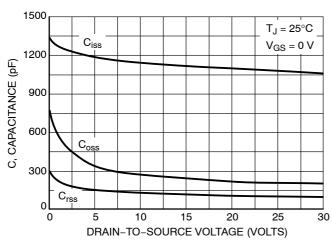


Figure 7. Capacitance Variation

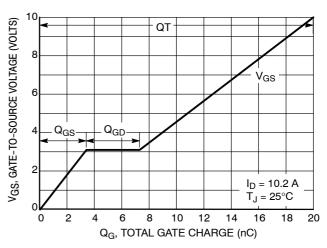


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

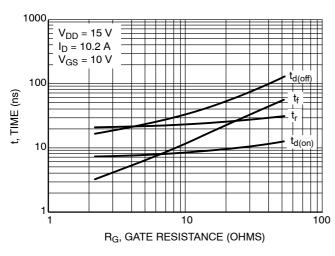


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

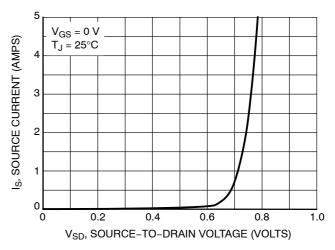


Figure 10. Diode Forward Voltage vs. Current

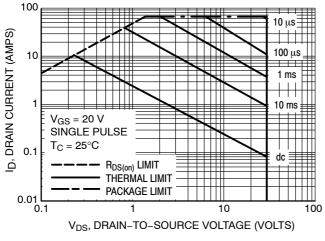


Figure 11. Maximum Rated Forward Biased Safe Operating Area

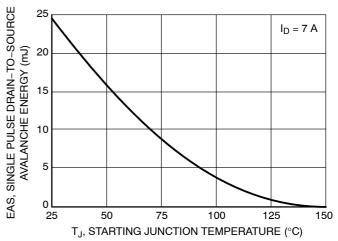
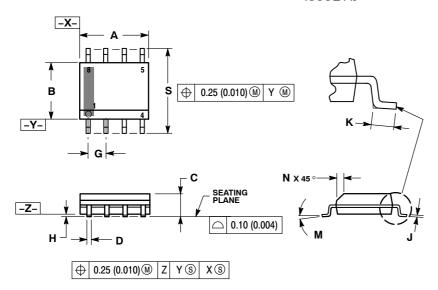


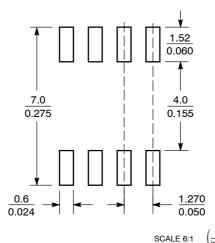
Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

SOIC-8 CASE 751-07 **ISSUE AJ**



SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES

- DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- PER SIJE.

 DIMENSION D DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL
 IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. 751-01 THRU 751-06 ARE OBSOLETE. NEW
- STANDARD IS 751-07.

	MILLIMETERS		INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27 BSC		0.05	0 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

- STYLE 12: PIN 1. SOURCE
 - 2. SOURCE
 - 3. SOURCE GATE 4.
 - DRAIN
 - DRAIN
 - 6. 7. DRAIN DRAIN

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